

Functional Safety Information

SN74LVC1G08-Q1

Functional Safety FIT Rate, FMD and Pin FMA



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1 Overview

This document contains information for the SN74LVC1G08-Q1 (DCK package) to aid in a functional safety system design. Information provided are:

- Functional safety failure in time (FIT) rates of the semiconductor component estimated by the application of industry reliability standards
- Component failure modes and their distribution (FMD) based on the primary function of the device
- Pin failure mode analysis (pin FMA)

Figure 1-1 shows the device functional block diagram for reference.



Figure 1-1. Functional Block Diagram

The SN74LVC1G08-Q1 was developed using a quality-managed development process, but was not developed in accordance with the IEC 61508 or ISO 26262 standards.

2 Functional Safety Failure In Time (FIT) Rates

This section provides functional safety failure in time (FIT) rates for the SN74LVC1G08-Q1 based on two different industry-wide used reliability standards:

- [Table 2-1](#) provides FIT rates based on IEC TR 62380 / ISO 26262 part 11
- [Table 2-2](#) provides FIT rates based on the Siemens Norm SN 29500-2

Table 2-1. Component Failure Rates per IEC TR 62380 / ISO 26262 Part 11

FIT IEC TR 62380 / ISO 26262	FIT (Failures Per 10 ⁹ Hours)					
	DBV	DCK	DRL	DRY	YZP	DPW
Total component FIT rate	5	4	4	5	3	4
Die FIT rate	3	3	3	4	2	3
Package FIT rate	2	1	1	1	1	1

The failure rate and mission profile information in [Table 2-1](#) comes from the reliability data handbook IEC TR 62380 / ISO 26262 part 11:

- Mission profile: Motor control from table 11
- Power dissipation: 50 mW
- Climate type: World-wide table 8
- Package factor (lambda 3): Table 17b
- Substrate material: FR4
- EOS FIT rate assumed: 0 FIT

Table 2-2. Component Failure Rates per Siemens Norm SN 29500-2

Table	Category	Reference FIT Rate	Reference Virtual T _J
3	CMOS Logic FCT, HC, LV, LVC, ALVC, VHC, and so forth	3 FIT	45°C

The reference FIT rate and reference virtual T_J (junction temperature) in [Table 2-2](#) come from the Siemens Norm SN 29500-2 tables 1 through 5. Failure rates under operating conditions are calculated from the reference failure rate and virtual junction temperature using conversion information in SN 29500-2 section 4.

3 Failure Mode Distribution (FMD)

The failure mode distribution estimation for the SN74LVC1G08-Q1 in [Table 3-1](#) comes from the combination of common failure modes listed in standards such as IEC 61508 and ISO 26262, the ratio of sub-circuit function size and complexity, and from best engineering judgment.

The failure modes listed in this section reflect random failure events and do not include failures resulting from misuse or overstress.

Table 3-1. Die Failure Modes and Distribution

Die Failure Modes	Failure Mode Distribution (%)
Stuck-at-fault	20%
Output open (HIZ)	20%
Output functional - out of specification timing or voltage	40%
Short circuit any two pins	20%

4 Pin Failure Mode Analysis (Pin FMA)

This section provides a failure mode analysis (FMA) for the pins of the SN74LVC1G08-Q1. The failure modes covered in this document include the typical pin-by-pin failure scenarios:

- Pin short-circuited to ground (see [Table 4-2](#))
- Pin open-circuited (see [Table 4-3](#))
- Pin short-circuited to an adjacent pin (see [Table 4-4](#))
- Pin short-circuited to supply (see [Table 4-5](#))

[Table 4-2](#) through [Table 4-5](#) also indicate how these pin conditions can affect the device as per the failure effects classification in [Table 4-1](#).

Table 4-1. TI Classification of Failure Effects

Class	Failure Effects
A	Potential device damage that affects functionality.
B	No device damage, but loss of functionality.
C	No device damage, but performance degradation.
D	No device damage, no impact to functionality or performance.

[Figure 4-1](#) shows the SN74LVC1G08-Q1 pin diagram. For a detailed description of the device pins, see the *Pin Configuration and Functions* section in the SN74LVC1G08-Q1 data sheet.

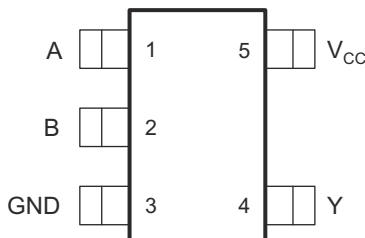


Figure 4-1. Pin Diagram

Table 4-2. Pin FMA for Device Pins Short-Circuited to Ground

Pin Name	Pin No.	Description of Potential Failure Effect(s)	Failure Effect Class
A, B	1, 2	Input pin functionality is defined such as input is LOW – see <i>Device Function Table</i> (for example, if buffer input is GND, output will always be driven LOW).	B
GND	3	Normal operation	D
Y	4	Can cause excessive output current, output will not switch (for example, if buffer output is shorted to ground and is attempting to drive to V_{CC}).	A
V_{CC}	5	Device will not be powered, because short is external to device. System level damage may occur in this scenario.	B

Table 4-3. Pin FMA for Device Pins Open-Circuited

Pin Name	Pin No.	Description of Potential Failure Effect(s)	Failure Effect Class
A, B	1, 2	Pin is floating, can change output state and cause excessive current from V_{CC} to GND. See Implications of Slow or Floating CMOS Inputs .	A
GND	3	Device will not be powered	B
Y	4	Normal operation	D
V_{CC}	5	Device will not be powered	B

Table 4-4. Pin FMA for Device Pins Short-Circuited to Adjacent Pin

Pin Name	Pin No.	Shorted to	Description of Potential Failure Effect(s)	Failure Effect Class
A, B	1, 2	A, B	Two inputs shorted together will not cause damage unless there is external bus contention that drives the input such that $V_{IL} < \text{Input Voltage} < V_{IH}$ in which case excessive supply current to GND may cause damage. System level damage may occur in this scenario.	A
A, B	1, 2	Y	Can cause excessive output current, output will not switch (for example, if inverter input is shorted to output).	A

Table 4-5. Pin FMA for Device Pins Short-Circuited to supply

Pin Name	Pin No.	Description of Potential Failure Effect(s)	Failure Effect Class
A, B	1, 2	Input pin functionality is defined such as input is HIGH – See Device Function Table (for example, if buffer input is V_{CC} , output will always be driven HIGH).	B
GND	3	Device will not be powered, because short is external to device. System level damage may occur in this scenario.	B
Y	4	Can cause excessive output current, output will not switch (for example, if buffer output is shorted to V_{CC} and is attempting to drive to GND).	A
V_{CC}	5	Normal operation	D

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